Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

1. (currently amended) A process method comprising:

forming an imprinted polymer disposed upon a substrate under conditions to expose a bond pad on the substrate by local flow of the polymer, wherein a recess is formed in the polymer;

mating attaching a solder bump with to the bond pad; and curing the polymer.

- 2. (currently amended) The process method of claim 1, further including comprising reflowing the solder bump at a process time selected from before curing the polymer, after curing the polymer, and simultaneously with curing the polymer.
- 3. (currently amended) The process method of claim 1, following forming an imprinted polymer the process further including comprising filling a solder flux into the recess.
- 4. (currently amended) The process method of claim 1, following forming un imprinted polymer the process further including comprising filling a solder flux into the recess by a process including comprising pushing the solder flux.
- 5. (currently amended) The process method of claim 1, wherein forming an imprinted polymer includes comprises forming the imprinted polymer with a convex over-all profile.
- 6. (currently amended) The process method of claim 1, wherein forming an imprinted polymer includes comprises forming the imprinted polymer with a convex over-all profile, and the process further including comprising:

mating attaching a microprocessor with to the solder bump.

7. (currently amended) The process method of claim 1, wherein forming an imprinted polymer includes comprises forming the imprinted polymer with a convex over-all profile, and the process further including comprising:

mating attaching a microprocessor with to the solder bump, wherein mating includes attaching comprises at least partially flattening the convex over-all profile.

- 8. (currently amended) The process method of claim 1, wherein forming an imprinted polymer includes comprises forming a contoured recess.
- 9. (currently amended) The process method of claim 1, wherein forming an imprinted polymer includes comprises forming a contoured recess, and wherein mating attaching the solder bump with to the bond pad includes mating attaching a complementary-contoured solder bump in the recess.
- 10. (currently amended) The process method of claim 1, further including mating comprising attaching a microprocessor with the solder bump.
- 11. (currently amended) The process method of claim 1, wherein the polymer is formed upon the substrate by depositing a prepolymer selected from a resin, an epoxy, and combinations thereof.
- 12. (currently amended) The process method of claim 1, wherein curing the polymer forms a cured polymer film that includes a film-to-substrate thickness ratio in a range from about one-tenth to about one-half the thickness of the substrate.
- 13. (currently amended) The process method of claim 1, wherein the polymer is formed upon the substrate by depositing a prepolymer selected from a resin, an epoxy, and combinations thereof, and wherein curing the polymer forms a cured polymer film including a film-to-substrate thickness ratio selected from about one-tenth, one-eighth, one-fourth, one-third, and one-half the thickness of the substrate.
- 14. (currently amended) The process method of claim 1, wherein the polymer is a resin that includes comprises a filler selected from silica, ceria, thoria, zirconia and combinations thereof.

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- 15. (currently amended) The process method of claim 1, wherein the polymer is a resin that includes comprises a filler selected from silica, ceria, thoria, zirconia and combinations thereof, and wherein the filler is selected from a spherical particle, an aspherical particle, a fiber, and combinations thereof.
- 16. (currently amended) The process method of claim 1, wherein the polymer is a resin that includes comprises a filler in a concentration range from about 30% to about 90%.
- 17. (currently amended) A process method comprising:

 placing a polymer film over a substrate;

 imprinting the polymer film under conditions to expose a bond pad on the substrate by local flow of the polymer film, wherein a recess is formed in the polymer film;

 mating attaching a solder bump with to the bond pad; and curing the polymer film.
- 18. (currently amended) The process method of claim 17, further including comprising reflowing the solder bump at a process time selected from before curing the polymer film, after curing the polymer film, and simultaneously with curing the polymer film.
- 19. (currently amended) The process method of claim 17, following forming an imprinted polymer film the process further including comprising filling a solder flux into the recess.
- 20. (currently amended) The process method of claim 17, following forming an imprinted polymer film the process further including comprising filling a solder flux into the recess by a process including comprising pushing the solder flux.
- 21. (currently amended) The process method of claim 17, wherein forming an imprinted polymer film includes comprises forming a contoured recess.
- 22. (currently amended) The process method of claim 17, wherein forming an imprinted polymer includes comprises forming a contoured recess, and wherein mating attaching the solder bump with to the bond pad includes mating comprises attaching a complementary-contoured solder bump in the recess.

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- 23. (currently amended) The process method of claim 17, further including mating comprising attaching a microprocessor with to the solder bump.
- 24. (currently amended) The process method of claim 17, wherein placing the polymer film upon the substrate-includes comprises placing a polymer film selected from a resin, an epoxy, and combinations thereof.
- 25. (currently amended) The process method of claim 17, wherein curing the polymer film forms a cured polymer film that includes comprises a film-to-substrate thickness ratio in a range from about one-tenth to about one-half the thickness of the substrate.
 - 26. (currently amended) The process method of claim 17, wherein placing the polymer film upon the substrate includes comprises placing a polymer film selected from a resin, an epoxy, and combinations thereof, and wherein curing the polymer film forms a cured polymer film including comprising a film-to-substrate thickness ratio selected from about one-tenth, one-eighth, one-fourth, one-third, and one-half the thickness of the substrate.

27.-29 (Canceled)

30. (currently amended) A process method comprising:

forming an imprinted polymer disposed upon a substrate under conditions to expose a bond pad on the substrate by local flow of the polymer, wherein a recess is formed in the polymer;

filling a solder flux into the recess;

mating attaching a solder bump with to the bond pad; and

curing the polymer, wherein curing the polymer forms a cured polymer film that includes comprises a film-to-substrate thickness ratio in a range from about one-tenth to about one-half the thickness of the substrate.

31. (currently amended) The process method of claim 30, wherein forming an imprinted polymer includes comprises forming the imprinted polymer with a convex over-all profile, and the process further including comprising:

mating attaching a microprocessor with to the solder hump.

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32. (currently amended) The process method of claim 30, wherein forming an imprinted polymer includes comprises forming a contoured recess.

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